

General Description

The WSD30150ADN56 is the highest performance trench N-Ch MOSFET with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

The WSD30150ADN56 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

Features

Advanced high cell density Trench technology Super Low Gate Charge Excellent CdV/dt effect decline 100% EAS Guaranteed Green Device Available

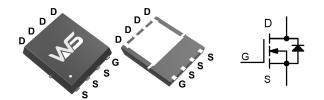
Product Summery

BVDSS	RDSON	ID
30V	2.2mΩ	145A

Applications

- High Frequency Point-of-Load Synchronous Buck Converter
- Networking DC-DC Power System
- Power Tool Application

DFN5X6-8 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	±20	V
I _D @T _C =25℃	Continuous Drain Current, V _{GS} @ 10V ^{1,7}	145	Α
I _D @T _C =100℃	Continuous Drain Current, V _{GS} @ 10V ^{1,7} 75		А
I _{DM}	Pulsed Drain Current ²	310	А
EAS	Single Pulse Avalanche Energy ³	372	mJ
I _{AS}	Avalanche Current 86		А
P _D @T _C =25℃	Total Power Dissipation⁴	78	W
T _{STG}	Storage Temperature Range -55 to 175		$^{\circ}$
TJ	Operating Junction Temperature Range -55 to 175		$^{\circ}$

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
$R_{ heta JA}$	Thermal Resistance Junction-Ambient ¹		55	°C/W
$R_{ heta JC}$	Thermal Resistance Junction-Case ¹		1.6	°C/W



N-Ch MOSFET

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	30			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =1mA		0.022		V/°C
В	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =20A		2.2	3.5	0
$R_{DS(ON)}$		V _{GS} =4.5V , I _D =15A		3.1	4.2	mΩ
V _{GS(th)}	Gate Threshold Voltage	\\ -\\ -250\	1.2	1.6	2.5	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D=250uA$		-6.1		mV/℃
	Drain Source Leakage Current	V _{DS} =24V , V _{GS} =0V , T _J =25°C V _{DS} =24V , V _{GS} =0V , T _J =55°C			2	uA
I _{DSS}	Drain-Source Leakage Current				10	
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA
gfs	Forwar Trd ansconductance	V _{DS} =5V , I _D =15A		32		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.1	2.5	Ω
Qg	Total Gate Charge (4.5V)	V _{DS} =15V , V _{GS} =4.5V , I _D =20A		22		
Q_{gs}	Gate-Source Charge			4.3		nC
Q _{gd}	Gate-Drain Charge			8.3		
T _{d(on)}	Turn-On Delay Time	V_{DD} =15V , V_{GEN} =10V , R_{G} =6 Ω , I_{D} =1A, R_{L} =15 Ω .		16		
Tr	Rise Time Rise Time			11		
T _{d(off)}	Turn-Off Delay Time			35		ns
T _f	Turn-Off Fall Time			40		
C _{iss}	Input Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		2450		
C _{oss}	Output Capacitance			590		pF
C _{rss}	Reverse Transfer Capacitance			245		

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	V _{DD} =25V , L=0.1mH , I _{AS} =15A	85			mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
I _S	Continuous Source Current ^{1,6}	V _G =V _D =0V , Force Current			50	Α
I _{SM}	Pulsed Source Current ^{2,6}				310	Α
V_{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =20A , T _J =25℃			1.2	V

Note:

- 1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, t<10sec.
- 2.The data tested by pulsed , pulse width $\leq 300 us$, duty cycle $\leq 2\%$
- 3. The EAS data shows Max. rating . The test condition is V_{DD} =25V, V_{GS} =10V,L=0.1mH, I_{AS} =20A
- 4. The power dissipation is limited by 150°C junction temperature
- 5. The Min. value is 100% EAS tested guarantee.
- 6. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.
- 7.Package limitation current is 100A.



N-Ch MOSFET

Typical Characteristics

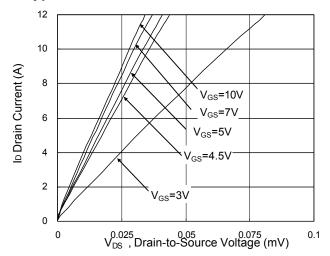


Fig.1 Typical Output Characteristics

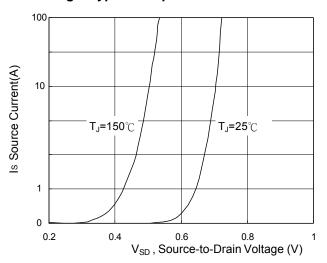


Fig.3 Forward Characteristics of Reverse

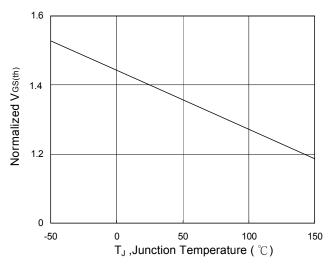


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

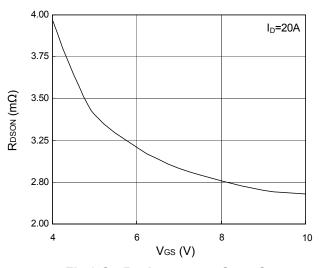


Fig.2 On-Resistance v.s Gate- Source

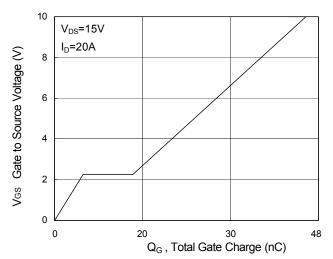


Fig.4 Gate-Charge Characteristics

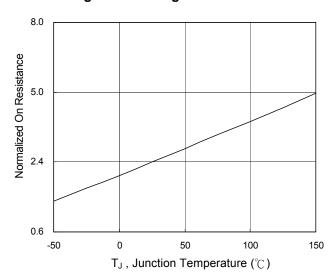
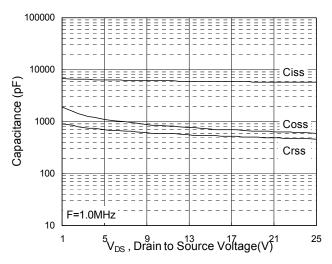


Fig.6 Normalized R_{DSON} v.s T_J



N-Ch MOSFET



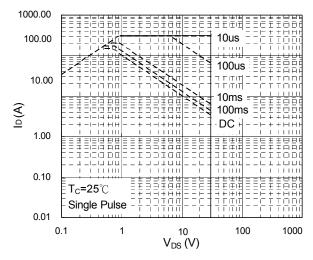


Fig.7 Capacitance

Fig.8 Safe Operating Area

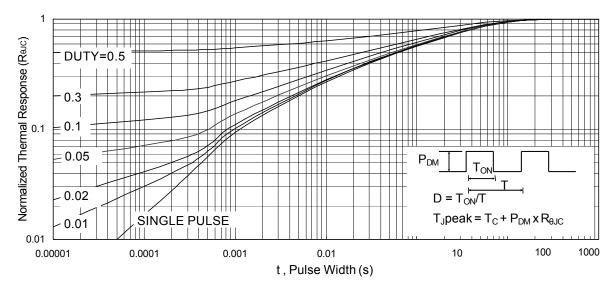
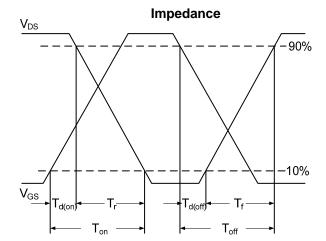


Fig.9 Normalized Maximum Transient Thermal



 $EAS = \frac{1}{2} L \times I_{AS}^{2} \times \frac{BV_{DSS}}{BV_{DSS}} - V_{DD}$ $BV_{DSS} - V_{DD} - V_{DD}$ $V_{DS} - V_{DD} - V_{DD}$

Fig.10 Switching Time Waveform

Fig.11 Unclamped Inductive Waveform



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